

TLP209D

MEASUREMENT INSTRUMENTS

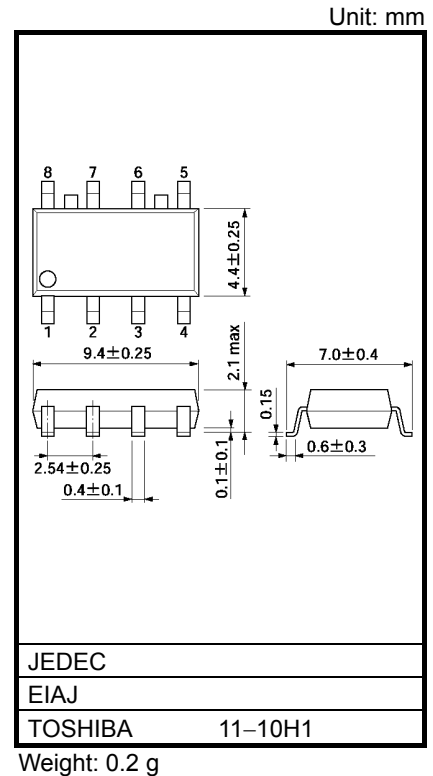
LOGIC IC TESTERS / MEMORY TESTERS

BOARD TESTERS / SCANNERS

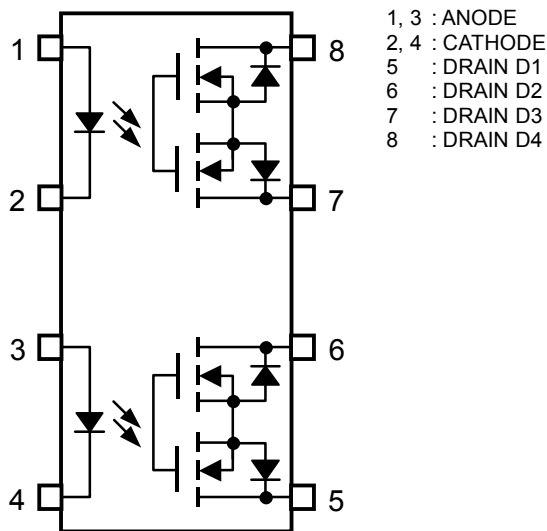
The TOSHIBA TLP209D consist of a gallium arsenide infrared emitting diode optically coupled to a photo-MOS FET in a plastic SOP package. Its characteristics include low OFF-state current and low output pin capacitance, enabling it to be used in high-frequency measurement instruments.

Features

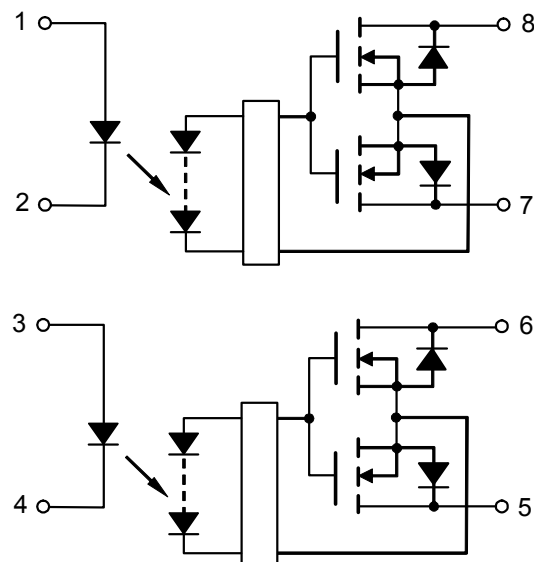
- 8 pin SOP (2.54SOP8) : 2.1 mm high, 2.54 mm pitch
- 2-Form-A
- Peak Off-State Voltage : 200 V (min)
- Trigger LED Current : 3 mA (max)
- On-State Current : 50 mA (max)
- On-State Resistance : 50 ohm (max)
- Output Capacitance : 20 pF (max)
- Isolation Voltage : 1500 Vrms (min)



Pin Configuration (top view)



Schematic



Absolute Maximum Ratings (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
LED	Forward Current	I_F	50	mA
	Forward Current Derating (Ta ≥ 25°C)	$\Delta I_F/^\circ\text{C}$	-0.5	mA/°C
	Reverse Voltage	V_R	5	V
	Junction Temperature	T_j	125	°C
DETECTOR	Off-State Output Terminal Voltage	V_{OFF}	200	V
	On-State Current	I_{ON}	50	mA
	On-State Current Derating (Ta ≥ 25°C)	$\Delta I_{ON}/^\circ\text{C}$	-0.5	mA/°C
	Junction Temperature	T_j	125	°C
Storage Temperature Range		T_{stg}	-55~125	°C
Operating Temperature Range		T_{opr}	-40~85	°C
Lead Soldering Temperature (10 s)		T_{sol}	260	°C
Isolation Voltage (AC, 1 minute, R.H. ≤ 60%) (NOTE1)		BV_S	1500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(NOTE1): Device considered a two-terminal device : LED side pins shorted together, and DETECTOR side pins shorted together.

Recommended Operating Conditions

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Supply Voltage	V_{DD}	—	—	160	V
Forward Current	I_F	5	7.5	15	mA
On-State Current	I_{ON}	—	—	50	mA
Operating Temperature	T_{opr}	-20	—	60	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Individual Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	Min	Typ.	Max	UNIT
LED	Forward Voltage	V_F	$I_F = 10 \text{ mA}$	1.0	1.15	1.3	V
	Reverse Current	I_R	$V_R = 5 \text{ V}$	—	—	10	μA
	Capacitance	C_T	$V = 0, f = 1 \text{ MHz}$	—	30	—	pF
DETECTOR	Off-State Current	I_{OFF}	$V_{OFF} = 160 \text{ V}$	—	—	1	nA
	Capacitance	C_{OFF}	$V = 0, f = 1 \text{ MHz}$	—	15	20	pF

Coupled Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Min	Typ.	Max	UNIT
Trigger LED Current	I_{FT}	$I_{ON} = 50 \text{ mA}$	—	1	3	mA
Return LED Current	I_{FC}	$I_{OFF} = 100 \text{ } \mu\text{A}$	0.1	—	—	mA
On-State Resistance	R_{ON}	$I_{ON} = 50 \text{ mA}, I_F = 5 \text{ mA}$	—	40	50	Ω

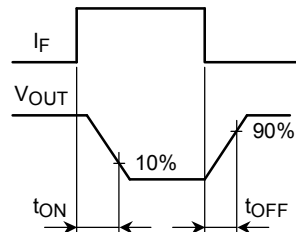
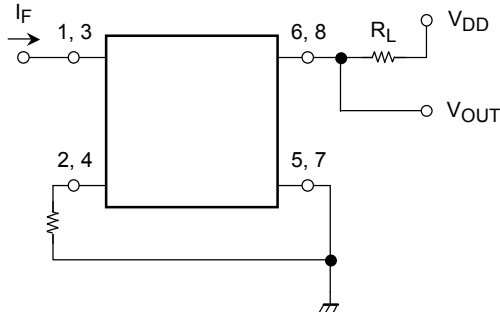
Isolation Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Min	Typ.	Max	UNIT
Capacitance Input to Output	C_S	$V_S = 0 \text{ V}, f = 1 \text{ MHz}$	—	0.8	—	pF
Isolation Resistance	R_S	$V_S = 500 \text{ V}, \text{R.H.} \leq 60\%$	5×10^{10}	10^{14}	—	Ω
Isolation Voltage	BV_S	AC, 1 minute	1500	—	—	Vrms
		AC, 1 second (in oil)	—	3000	—	—
		DC, 1 minute (in oil)	—	3000	—	Vdc

Switching Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Min	Typ.	Max	UNIT
Turn-on Time	t_{ON}	$R_L = 200 \text{ } \Omega$ (NOTE 2) $V_{DD} = 10 \text{ V}, I_F = 5 \text{ mA}$	—	0.03	0.5	ms
Turn-off Time	t_{OFF}		—	0.07	0.2	

(NOTE 2) : SWITCHING TIME TEST CIRCUIT



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